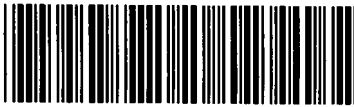


Search Notes

Application/Control No.

10/733,416

Examiner

Yonel Beaulieu

Applicant(s)/Patent under
Reexamination

SAKURAI ET AL.

Art Unit

3661

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SEARCHED

Class	Subclass	Date	Examiner
701	22	4/1/2007	YB
	36		
307	9.1		
	10.1		
	10.6		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST+Interference+Bwd/Fwd	4/2/2007	YB